

<b>Notice of References Cited</b>	Application/Control No. 10/658,576	Applicant(s)/Patent Under Reexamination MEI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,635,700	10-2003	Cruse et al.	524/262
	B	US-			
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	D	US-			
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	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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